

<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Atty Docket No. <b>NIKOP064/PA0647</b>	<b>10578752</b>
	Applicant: <b>Alton, et al.</b>	<b>To Be Assigned</b>
	Filing Date <b>May 4, 2006</b>	Group <b>To Be Assigned</b>

**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	1A	6,090,176	07/18/00	Yoshitake, et al.			03/11/98
	1B	6,239,863	05/29/01	Catey, et al.			12/29/99
	1C	6,281,510	08/28/01	Yoshitake, et al.			05/02/00
	1D	6,317,479	11/13/01	Chiba, et al.			05/16/97
	1E	6,646,720	11/11/03	Ramamoorthy, et al.			09/21/01
	1F	6,728,332	04/27/04	Chiba, et al.			10/05/01
	1G	6,753,945	06/22/04	Heerens, et al.			02/27/03
	1H	6,906,783	06/14/05	del Puerto, et al.			02/20/03
	1I	6,826,451	11/30/04	del Puerto, et al.			08/22/02
	1J	6,912,043	06/28/05	Galburt			10/27/03

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	1K	1491960A2	29/12/04	EP			X	
	1L	1120690A2	01/08/01	EP			X	

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	1M	Rader, Daniel J., et al., <i>Verification studies of thermophoretic protection for EUV masks</i> , Emerging Lithographic Technologies VI, Proceedings of SPIE Vol. 4688 (2002), pp. 182-193.
Examiner	Steven Whitesell Gordon/ (07/26/2010)	
	Date Considered	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	2A	6,253,464	07/03/01	Klebanoff, et al.			08/18/00
	2B	6,153,044	11/28/00	Klebanoff, et al.			04/30/98
	2C	6,414,744	07/02/02	Kuiper, et al.			04/19/00
	2D	2002/0096647	07/25/02	Moors, et al.			10/09/01
	2E	6,492,067	12/10/02	Klebanoff, et al.			12/03/99
	2F	6,153,044	11/28/00	Klebanoff, et al.			04/30/98
	2G	5,061,444	10/29/91	Nazaroff, et al.			03/22/91
	2H	5,169,272	12/08/92	Bonora, et al.			11/01/90
	2I	2003/0082030	05/01/03	del Puerto, et al.			08/12/02

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